PCN Number: 20210730004.3			.1B			PC	N Date:	August 25, 2021			
Titl	Comparison Compari										
Cus	tomer Contact:		PCN Manager			Dept:	Quality Se	ervio	es		
Pro Dat	posed 1 st Ship :e:		Nov 02, 2	202	1	Estimaton Sample Availability			Provided upon Request		
Cha	Change Type:										
Assembly Site			sign 📃 🗌 Wafer Bump Site			mp Site					
	Assembly Proces	s			Data	a Sheet			Wafer Bump Material		
\boxtimes	Assembly Mater	als			Part	number cl	number change 🛛 🗌 Wafer Bump Process			mp Process	
	Mechanical Spec	ific	ation		Test	: Site			Wafer Fa	b Site	
Packing/Shipping/Labeling 🗌 Test I			Process			Wafer Fa	b Materials				
	Wafer Fab Process										
	PCN Details										
Des	scription of Cha	nge	9:								
D	Providing D is to account TDCE(2221DDLD/T from One on 2 devices Ukablighted and holded										

Revision B is to remove TPS562231DRLR/T from **Group 2** devices. Highlighted and bolded devices are additional devices that was not included on the original PCN notification issued under rev A. The expected first shipment date for the new device will be 90 days from this notice (Nov 20, 2021) for the newly added device only. The proposed 1st ship date of Nov 02, 2021 still applies for the original set of devices.

Texas Instruments Incorporated is announcing the qualification of additional Assembly sites for devices listed below in the product affected section. Construction differences and current assembly sites are as follows:

Group 1 Device:

SOT-5X3 (DRL)			
Assembly Sites	TIPI, HNA, JCETC8, JCETJY,		
	CDAT		
Lead Finish	Matte Sn		
	4222198		
Mold Compound	450214		
	111020003809		

Group 2 Device:

SOT	SOT-23 (DDC)		
Assembly Sites	TIPI, HNA, UTL, JCETC8, JCETJY,		
	CDAT, TIEM		
Lead Finish	Matte Sn		
	4222198		
	450207		
Mold Compound	8097131		
	120800005407		

Reason for Change:

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative): None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Stat		IEC 6247	4	
No Change	No Change	No Change		No Change	-	
	Changes to product identification resulting from this PCN: Assembly Site					
TI Philippines	Assembly Site Origin (2	22L) ASO: PHI				
Hana	Assembly Site Origin (2	,				
UTL	Assembly Site Origin (2					
JCETC8	Assembly Site Origin (2		_			
JCETJY	Assembly Site Origin (2					
TI Chengdu	Assembly Site Origin (2	22L) ASO: CDA				
TI Melaka	Assembly Site Origin (2	22L) ASO: CU6				
MADE IN: Malaysia 2DC: 2Q: MSL '2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/0 OPT: ITEM: 39 LBL: 5A (L)T0:1750	INSTRUMENTS G4 MADE IN: Malaysia 20: MSL '2 /260C/1 YEAR SEAL DT MG4 22: MSL '2 /260C/1 YEAR SEAL DT MG4 22: OPT: 1/235C/UNLIM JTEM: 39					
TPS562231DRLR	TPS562231DRLT					
Group 2 Product Affec						
SN1501019ADDCR		PS54202HDDCT	TPS56324			
SN1501019DDCR		PS561201DDCR	TPS56324			
SN1501019DDCT		PS561201DDCT	TPS56324			
SN1501020DDCR		PS561208DDCR	TPS56324			
SN1501020DDCT		PS561208DDCT	TPS5633			
SN1504025DDCR		PS562200DDCR	TPS5633			
SN1504025DDCT		PS562200DDCT	TPS56420			
SN1504026DDCR		PS562209DDCR	TPS56420			
SN1504026DDCT		PS562209DDCT	TPS56420			
SN1611045DDCR		PS562231DRLR	TPS56420			
SN1702049DDCR		PS562231DRLT	TPS9220	0D1DDCR		
SN1704026DDCR		PS563200DDCR	TPS9220	0D2DDCR		
SN1704026DDCT	TPS54202DDCR TI	PS563200DDCT				
SN1706011DDCR	TPS54202DDCT TI	PS563209DDCR				
SN1706011DDCT	TPS54202HDDCR TI	PS563209DDCT				

Group 1 Qualification Report (SOT-5X3)

Qualification Results

	Data Displayed as: Num			
	Stress Test	Duration	TIPI TLV62568DRL	CDAT TPS562231DRL
тс	Temperature Cycling - 65/150C	500 Cycles	3/231/0	3/231/0
HAST	Biased HAST 130C/85%RH	96 hours	3/231/0	3/231/0
HTSL	High Temp. Storage Bake 150C	1000 hours	-	-
HTSL	High Temp. Storage Bake 170C	420 hours	3/231/0	3/231/0
UHAS T	Unbiased HAST, 130C/85%RH	96 hours	-	3/231/0
AC	Autoclave 121C	96 hours	3/231/0	-
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0	3/66/0
MQ	Manufacturability	-	Pass	Pass

	Stress Test	Duration	JCETC8 TLV62568PDRL	HNA TMP390A2DRL	JCETJY TMP302BDRL
TC	Temperature Cycling - 65/150C	500 Cycles	3/231/0	3/231/0	3/231/0
HAST	Biased HAST 130C/85%RH	96 hours	3/231/0	-	3/231/0
HTSL	Biased HAST 110C/85%RH	264 hours	-	3/231/0	-
HTSL	High Temp. Storage Bake 170C	420 hours	3/231/0	3/231/0	3/231/0 (b)
UHAST	Unbiased HAST, 130C/85%RH	96 hours	-	3/231/0	3/231/0
AC	Autoclave 121C	96 hours	3/231/0	-	-
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0	3/66/0 (a)	3/66/0 (b)
MQ	Manufacturability	-	Pass	Pass	Pass

All qualification devices in the tables are qualified at L1-260C MSL rating.

Note a - Data collected on SN74AVC1T45DRL

Note b – Data collected on TMP102AIDRL and TMP302BDRL

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, and HTSL, as applicable

- The following are equivalent HTSL options based on activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

Quality and Environmental data is available at TI's external Web site: <u>http://www.ti.com/</u> **Green/Pb-free Status:** Qualified Pb-Free(SMT) and Green

Group 2 Qualification Report (SOT-23)

Qualification Results

	Data Displayed as: Number of lots / Total sample size / Total failed						
	Stress Test	Duration	TIPI TPS563249DDC	CDAT TPS563249DDC			
тс	Temperature Cycling - 65/150C	500 Cycles	3/231/0	3/231/0			
HAST	Biased HAST 130C/85%RH	96 hours	3/231/0	3/231/0			
HTSL	High Temp. Storage Bake 150C	1000 hours	-	-			
HTSL	High Temp. Storage Bake 170C	420 hours	3/231/0	3/231/0			
UHAS T	Unbiased HAST, 130C/85%RH	96 hours	3/231/0	3/231/0			
AC	Autoclave 121C	96 hours	-	-			
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0 (TPS563201DDC)	3/66/0			
MQ	Manufacturability	-	Pass	Pass			

	Stress Test	Duration	JCETC8 TPS563208DDC	JCETJY TLV62569PDDC
тс	Temperature Cycling - 65/150C	500 Cycles	3/231/0	3/231/0
HAST	Biased HAST 130C/85%RH	96 hours	3/231/0	3/231/0
HTSL	High Temp. Storage Bake 150C	1000 hours	-	-
HTSL	High Temp. Storage Bake 170C	420 hours	3/231/0	3/231/0
UHAS T	Unbiased HAST, 130C/85%RH	96 hours	3/231/0	-
AC	Autoclave 121C	96 hours	-	3/231/0
SD	Solderability	8 Hour Steam age or 155C Dry Bake	3/66/0	3/66/0 (TPS27081ADDC)
MQ	Manufacturability	-	Pass	Pass

	Stress Test	Duration	UTL LM73CxQDDCRQ 1	TIEM TPL5010QDDCR Q1	HNA LV2862XLVDD C
тс	Temperature Cycling - 65/150C	500 Cycles	3/231/0	3/231/0	3/231/0
HAST	HAST Biased HAST 130C/85%RH		3/231/0	3/231/0	3/231/0
HTSL	High Temp. Storage Bake 150C	1000 hours	-	3/231/0	-
HTSL	High Temp. Storage Bake 170C	420 hours	3/231/0 (a)	-	3/135/0 (b)
UHAST	Unbiased HAST, 130C/85%RH	96 hours	-	3/231/0	-
AC	Autoclave 121C	96 hours	3/231/0	-	3/231/0
SD	Solderability	8 Hour Steam	2/44/0 (TPS62242QDDC)	2/44/0 (LM2734XQMK)	3/66/0 (b)

	Stress Test	Duration	UTL LM73CxQDDCRQ 1	TIEM TPL5010QDDCR Q1	HNA LV2862XLVDD C
		age or 155C Dry Bake			
MQ	Manufacturability	-	Pass	Pass	Pass

All qualification devices in the tables are qualified at L1-260C MSL rating.

Note a – Data collected on TPS3702EX33QDDCRQ1 and LM73CxQDDCRQ1 Note b – Data collected on LMP8640QMKX-T/NOPB

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, and HTSL, as applicable

- The following are equivalent HTSL options based on activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

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